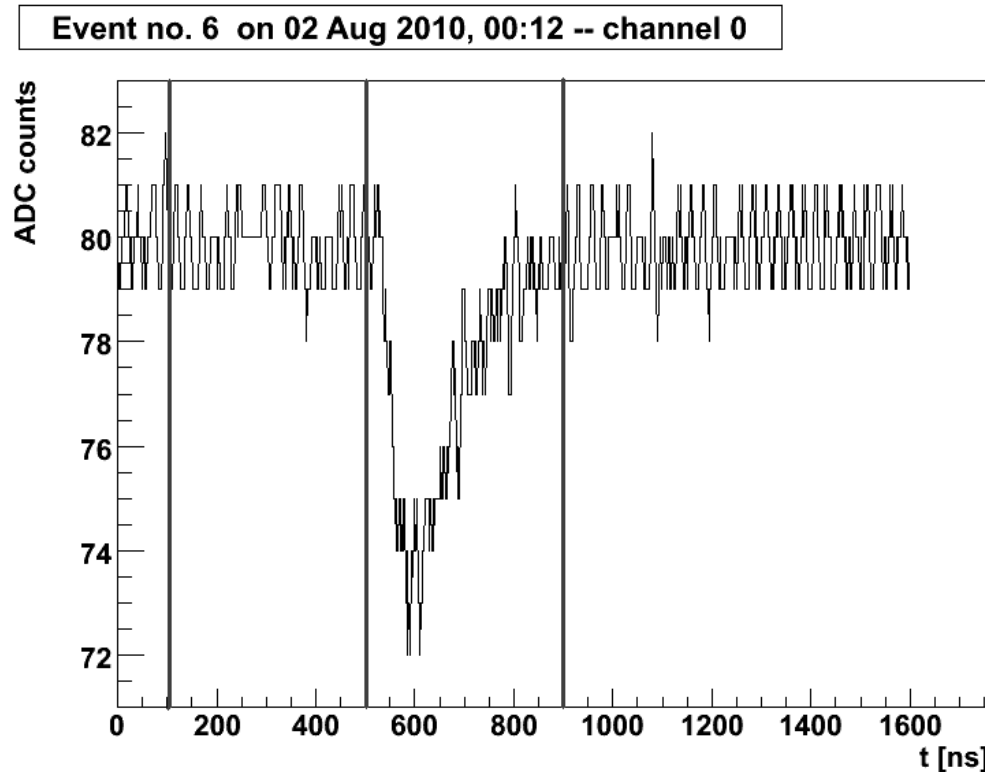


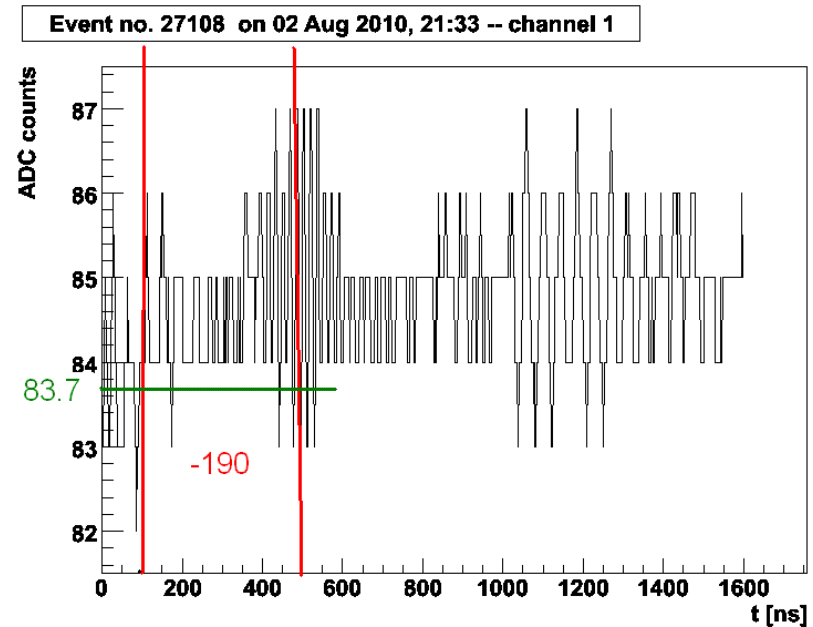
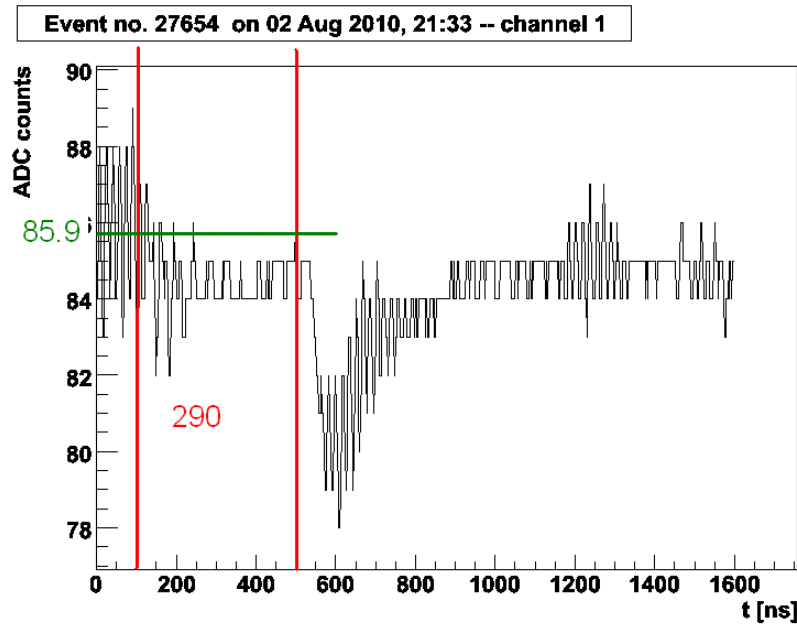
Integration with averaged
baseline

Old method



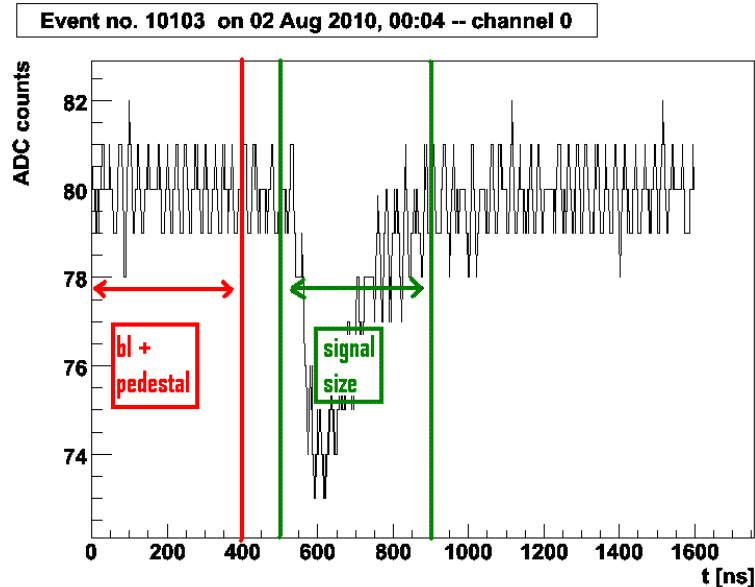
- First 50 samples for baseline
- Samples 50 to 249 for pedestal
- Samples 250 to 449 for signal

Old method



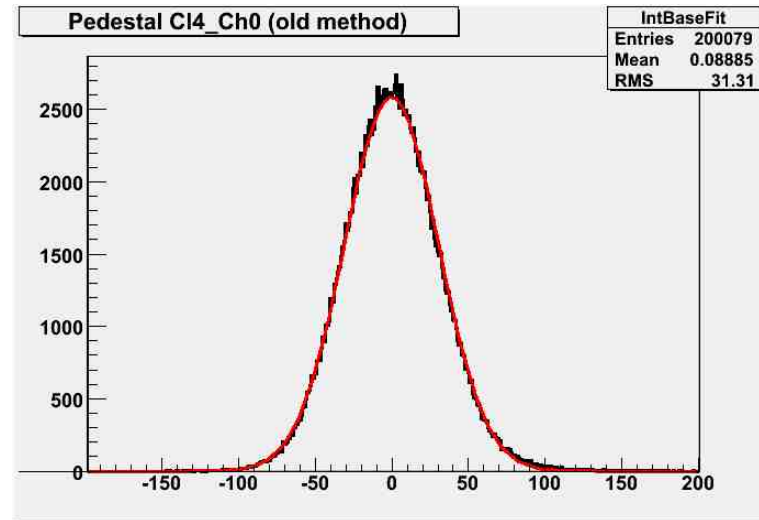
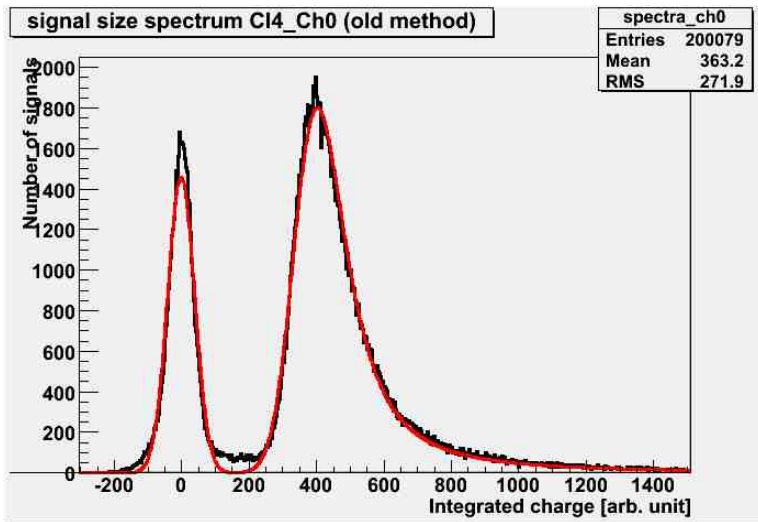
- Noise in the window for baseline calculation leads miscalculation for integrals
- Baseline window 50 samples, integrations over 200 samples => width of pedestal mainly given by error of baseline (Sergej)

New method

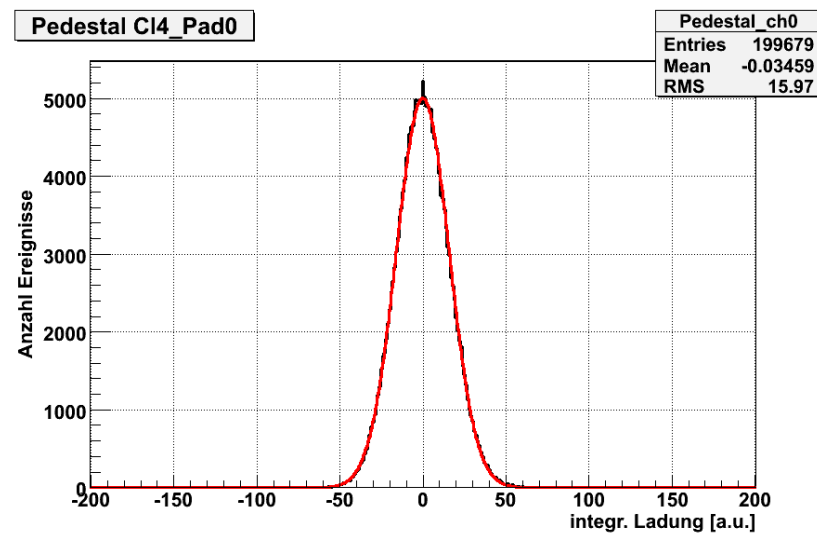
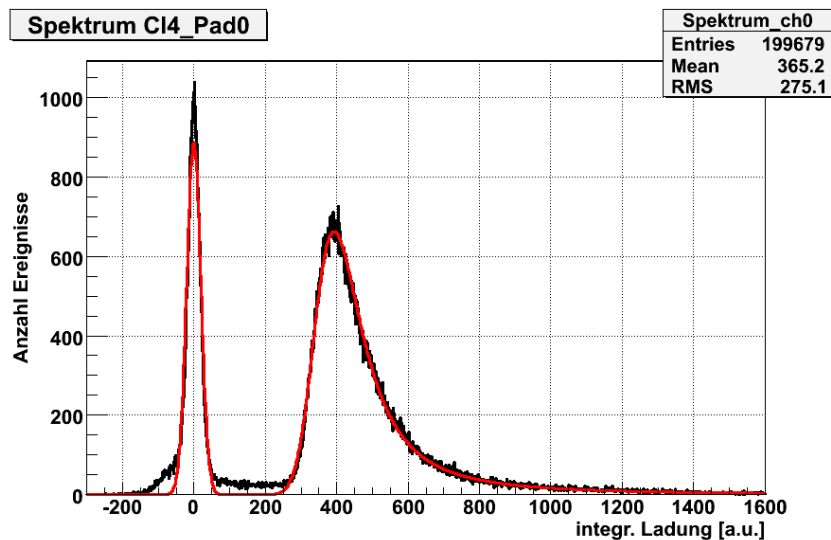


- Two windows for calculations
- First $\{0 \dots 199\}$ samples for baselines and pedestal
- Samples $\{200 \dots 449\}$ for signal size
- Calculating baselines for events $(N-1) \dots (N-101)$
- Take mean value as baseline for event N
- Integrate with respect to the baseline over first window (pedestal) and second one (signal size) for event N
- First 100 events in each root file were taken to calculate initial baseline mean value ($\sim 0.2\%$ of data)

Comparison - spectra



old

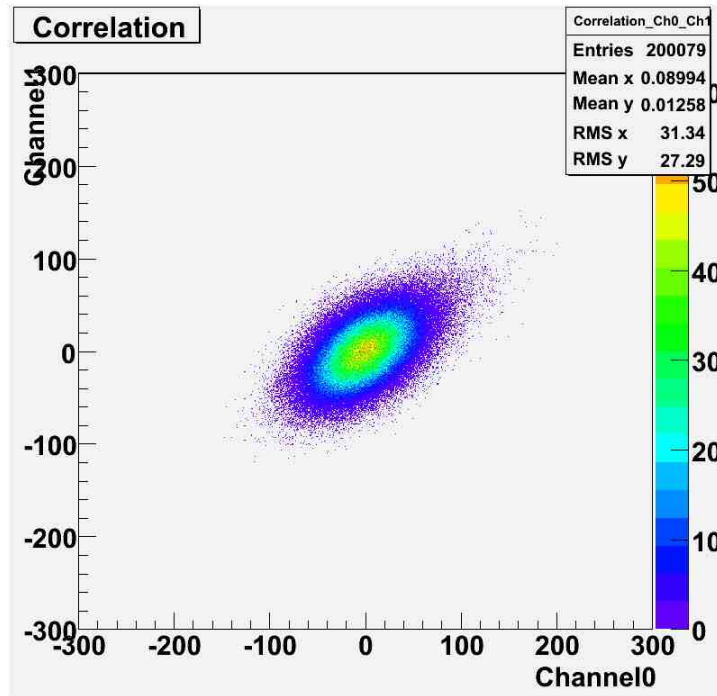


new

Cluster2						new		
Pad	gegenkopp	gnal (M2) [a	ma (M2) [a	S/N		Signal [au]	Sigma[au]	S/N
0	MOSFET	373.7	35.7	10.5		372.6	15.2	24.5
1	MOSFET	361.7	32.4	11.2		358.7	17.0	21.1
2	MOSFET	382.9	33.6	11.4		382.0	14.4	26.5
3	MOSFET	386.4	34.6	11.2		384.6	16.1	23.9
4	RC	184.1	15.7	11.7		183.0	9.3	19.7
5	MOSFET	391.7	33.6	11.7		391.3	18.4	21.3
6	RC	173.4	23.2	7.5		172.5	14.1	12.2
7	MOSFET	375.7	31.7	11.9		375.0	14.0	26.8
Cluster 4								
Pad	gegenkopp	gnal (M2) [a	ma (M2) [a	S/N		Signal [au]	Sigma [au]	S/N
0	MOSFET	382.7	30.7	12.5		381.6	15.9	24.0
1	MOSFET	372.1	27.9	13.3		370.8	14.3	25.9
2	MOSFET	372.7	27.0	13.8		372.0	13.5	27.6
3	MOSFET	386.6	25.5	15.2		385.7	12.3	31.4
4	RC	182.9	16.0	11.4		182.0	9.7	18.8
5	RC	174.3	16.6	10.5		173.2	10.1	17.1
6	RC	175.2	18.2	9.6		174.3	10.7	16.3
7	RC	177.5	17.8	10.0		176.5	10.6	16.7

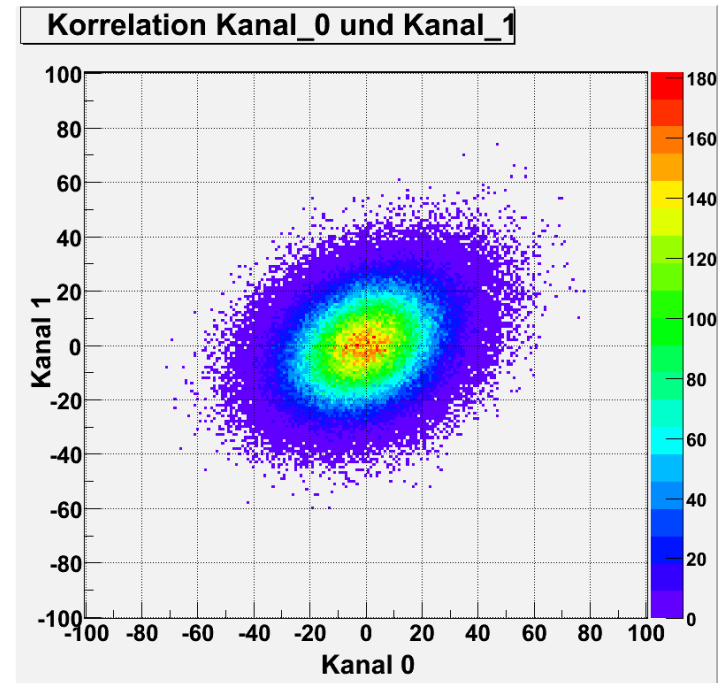
Comparison – correlation (for pedestals)

old



CorrCoeff ~ 0.54

new



CorrCoeff ~ 0.29